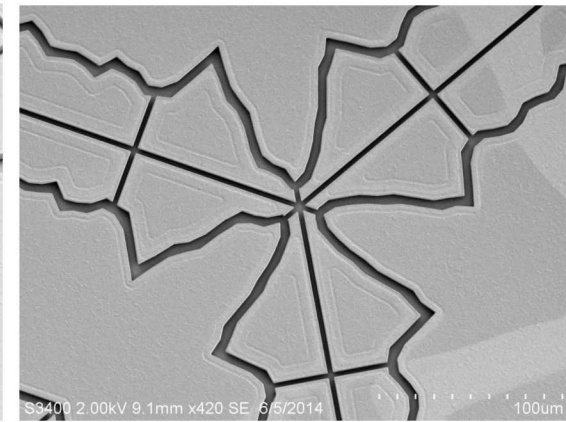
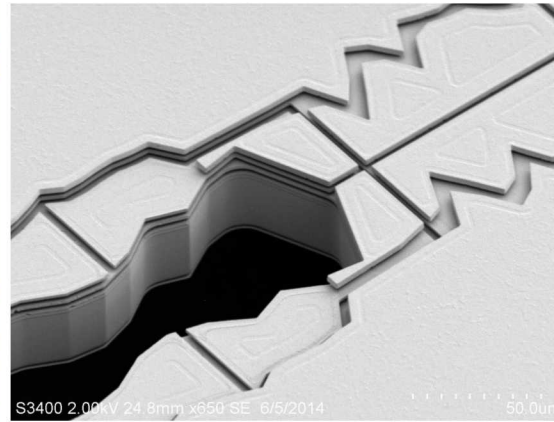
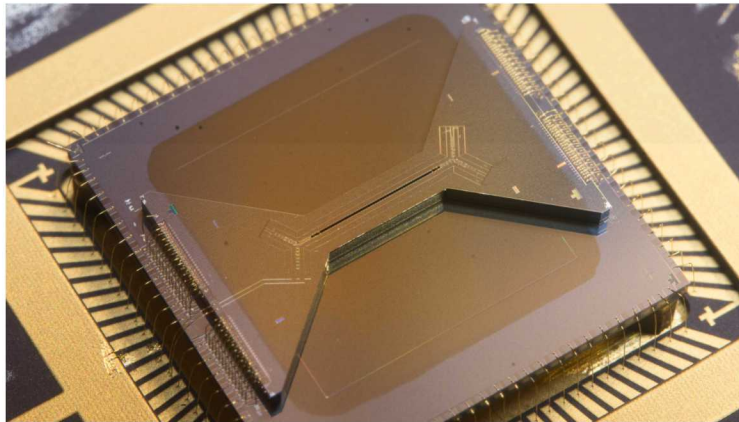


[Redacted text]

[Redacted text]



Trapped Ion Experiments at Sandia National Laboratories Waterloo 2018



Susan Clark, Sandia National Laboratories



Sandia National Laboratories is a multimission laboratory managed and operated by National Technology & Engineering Solutions of Sandia, LLC, a wholly owned subsidiary of Honeywell International, Inc., for the U.S. Department of Energy's National Nuclear Security Administration under contract DE-NA0003525.

AMO Physics at Sandia

Trapped Ions:

- Surface trap fabrication

- Ion shuttling and reordering

- Characterization of high fidelity quantum gates with Gate Set Tomography (GST)

- Ion Clocks

Neutral Atoms:

- Two-qubit gates

- Atom interferometry

Solid State (AMO-like):

- Phosphorous donors in Silicon

- Quantum Dots

- CINT

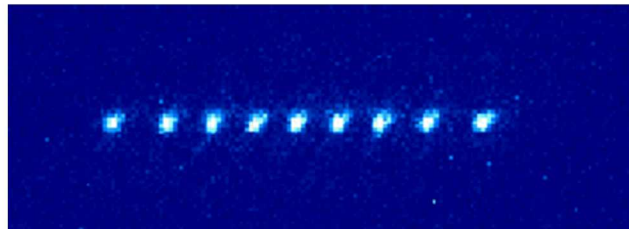
Uses of Trapped Ions

Mass Spectrometry: Identify substances by mass to charge ratio

Isotope dating and tracking, Trace gas analysis, protein characterization, space exploration (mars rover), antiproton storage at CERN, drinking water safety...

Precision clocks: Narrow transitions allow for accurate time standards

Quantum information: Electron spin for simulation and memory



Ions for Quantum Information

Quantum Experimental Platforms answer questions about:

- 1) The nature of information
- 2) Fundamentals of quantum mechanics
- 3) Secure information transfer
- 4) Simulating more complicated systems
- 5) New types of computing resources for certain problems

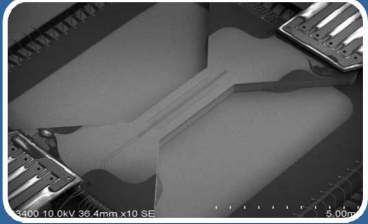
Main Advantages of Ions:

Well understood and mature system

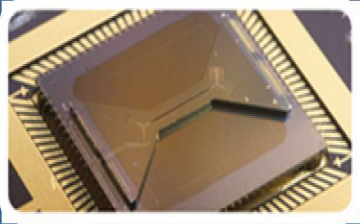
Main sources of error are classical control problems

(microwaves/lasers/electric field noise/varying magnetic fields)

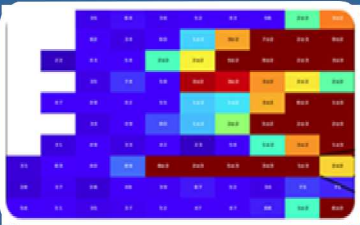
Outline



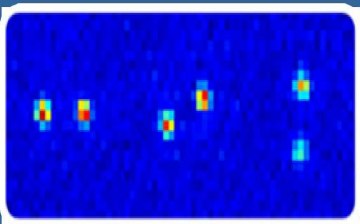
Trap fabrication, advantages and challenges



Example trap designs: High Optical Access trap & Microwave trap



Characterization of quantum gates using Gate Set Tomography (GST)

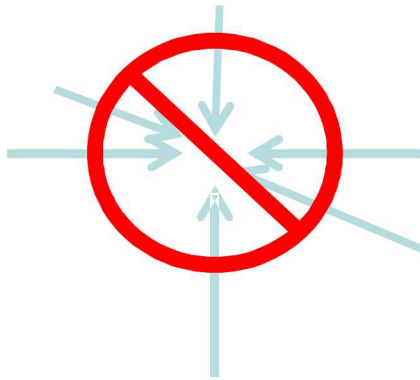


Recent Results in Surface Traps: Ion shuttling, high fidelity operations, sympathetic cooling

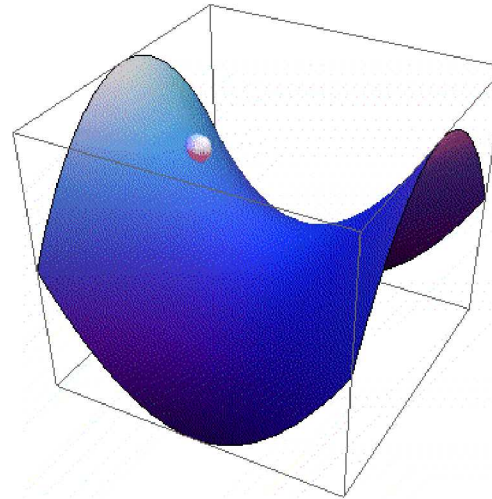
Earnshaw's Theorem and Ion Trapping

Trapping requirement: A restoring force when displaced from trap center
(in any direction)

Cannot use static electric fields to
trap a charge
Field lines cannot cross, and must
start/end on sources/drains



Before ion
escapes, field
reverses!

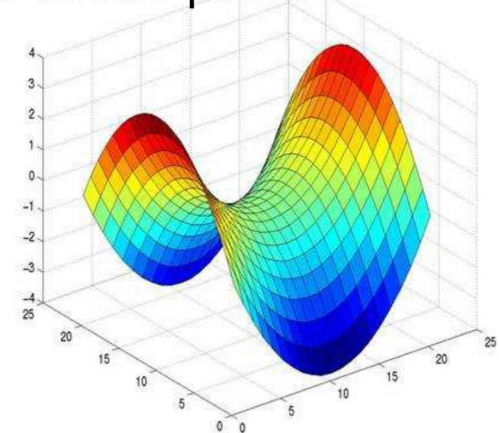
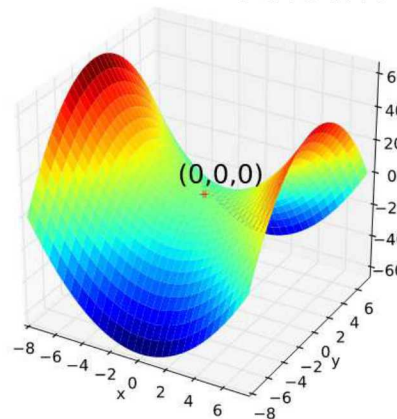


create
S



Courtesy of Wes
Campbell

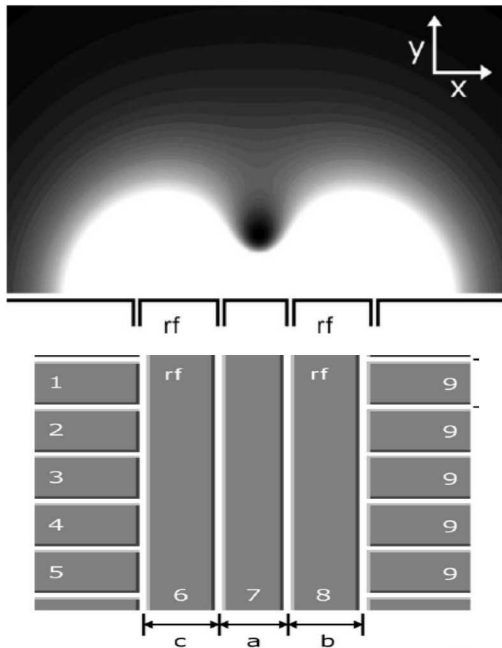
Known as saddle points



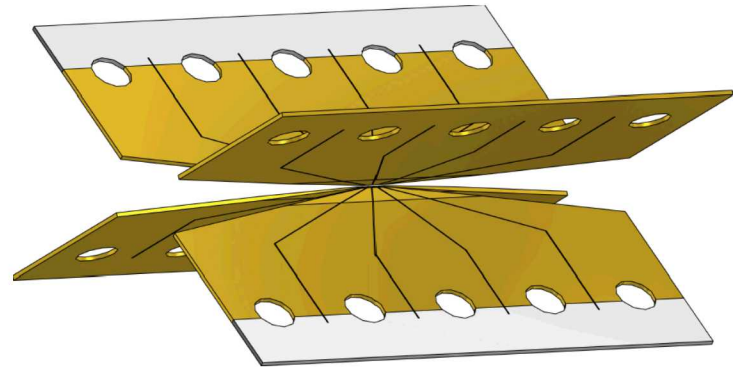
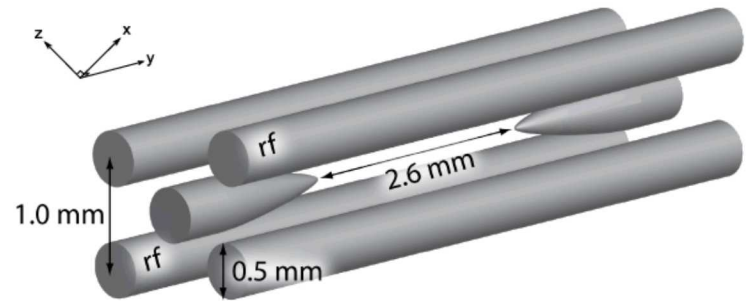
Various trap geometries

Use a combination of static and rf fields to trap ions
Various geometries possible

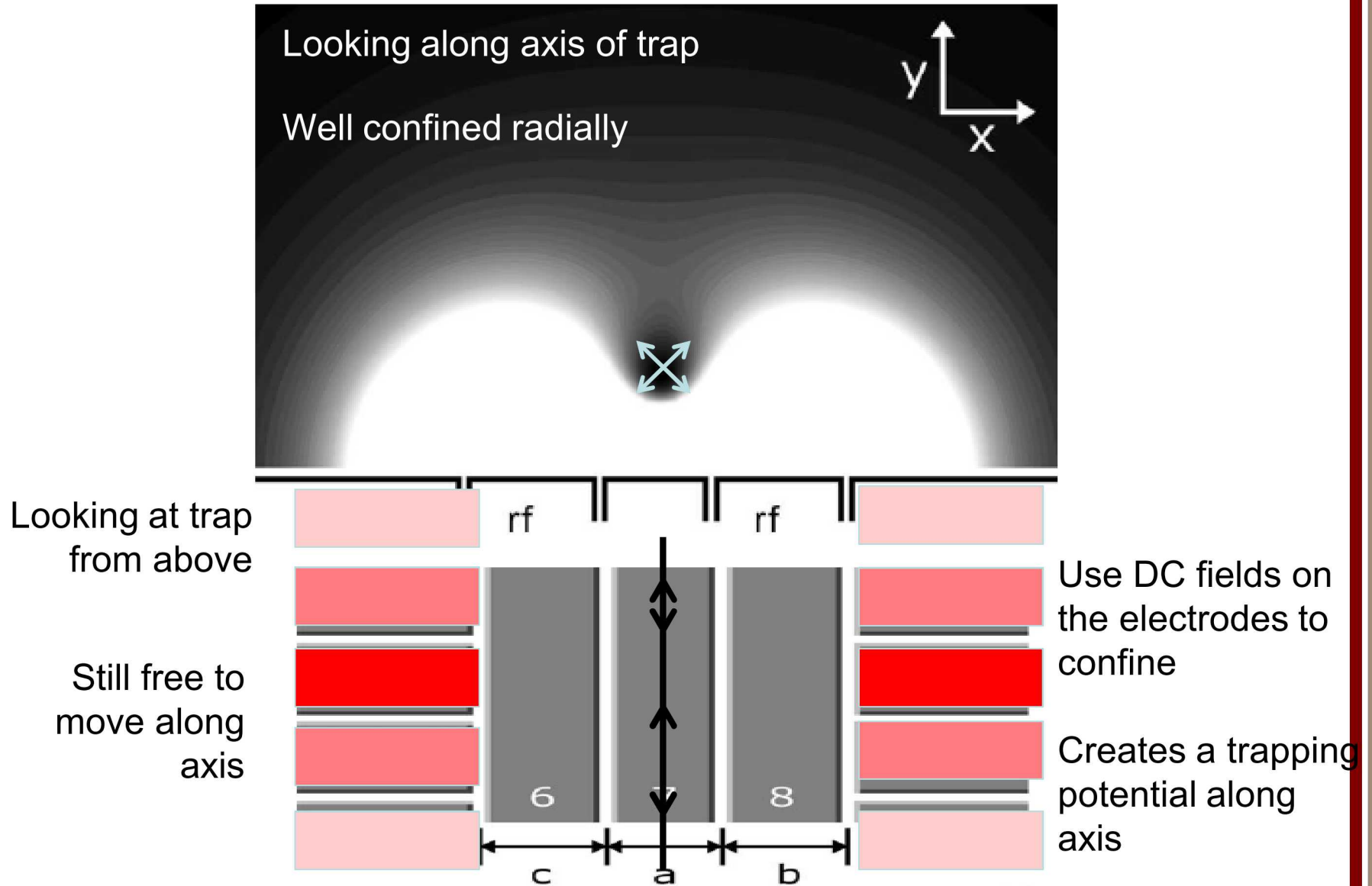
Pseudopotential well (dark area) formed along the axis of a surface trap



Electrodes from above



Need for DC fields



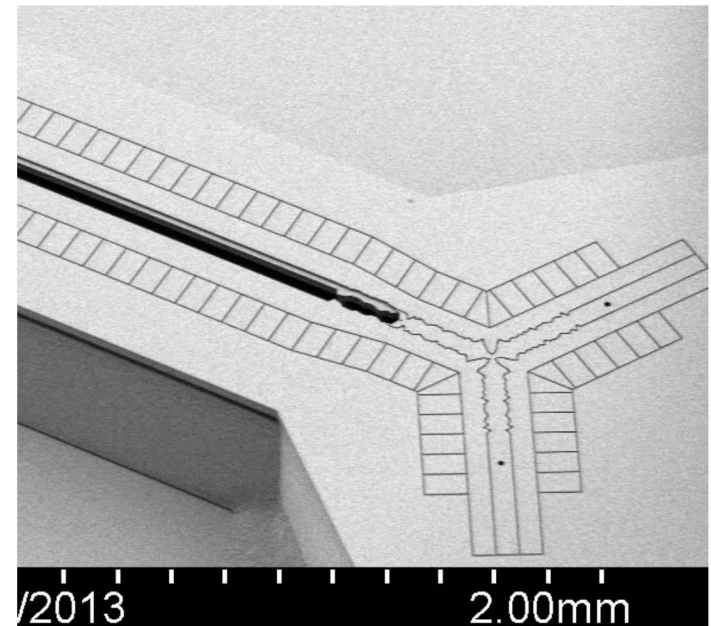
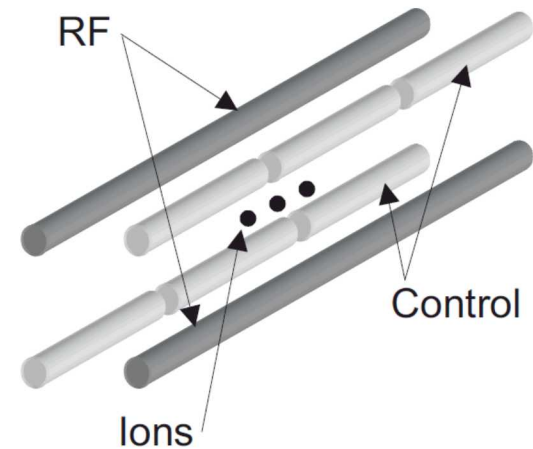
Advantages/Challenges vs 3D

Advantages

- Greater field control (more electrodes)
- Flexible, precise 2D geometry
- More manufacturable
- Consistent geometry → consistent behavior
- Laser access
- Integration of other technologies (waveguides, detectors, filters...)

Challenges

- Lower depth (ion lifetime), anharmonicities in potential
- Proximity to surface (charging, heating)
- Delicate (dust, voltage)
- Capacitance
- Laser access



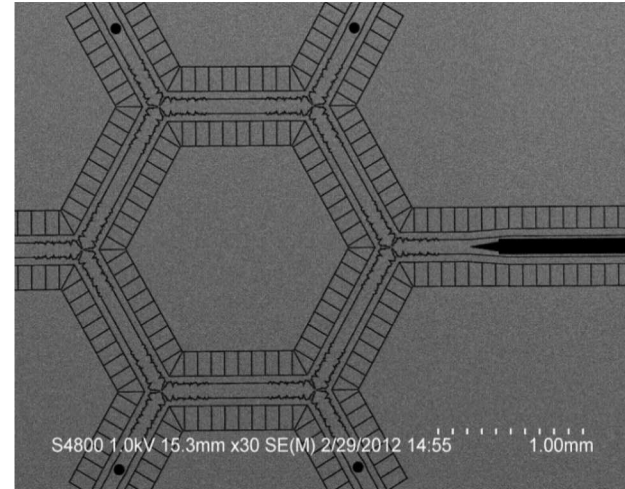
Capabilities & Requirements

Essential capabilities

- Reliable and consistent operation
- Store ions for long periods of time (hours)
- Move ions to achieve 2D connectivity
- Support high fidelity operations

MESA facility

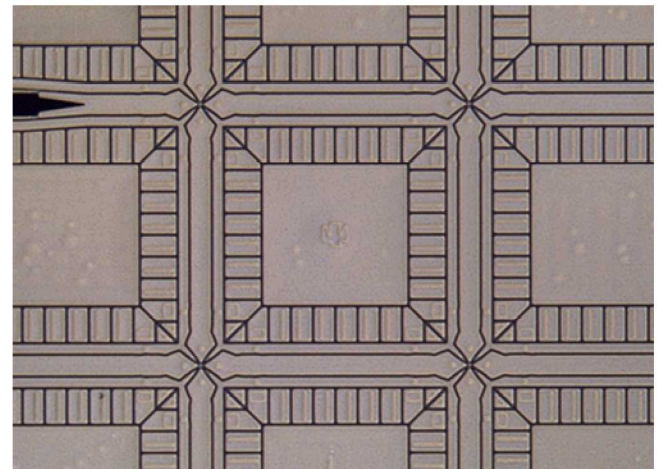
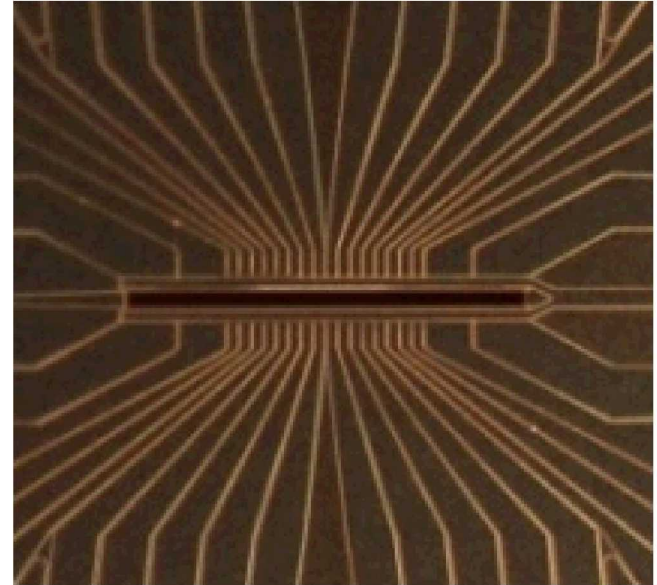
- Radiation hardened CMOS
- Leverages reliability of NW processing
- Large feature sizes (350 nm) match well with trap requirements



Capabilities & Requirements

Derived requirements

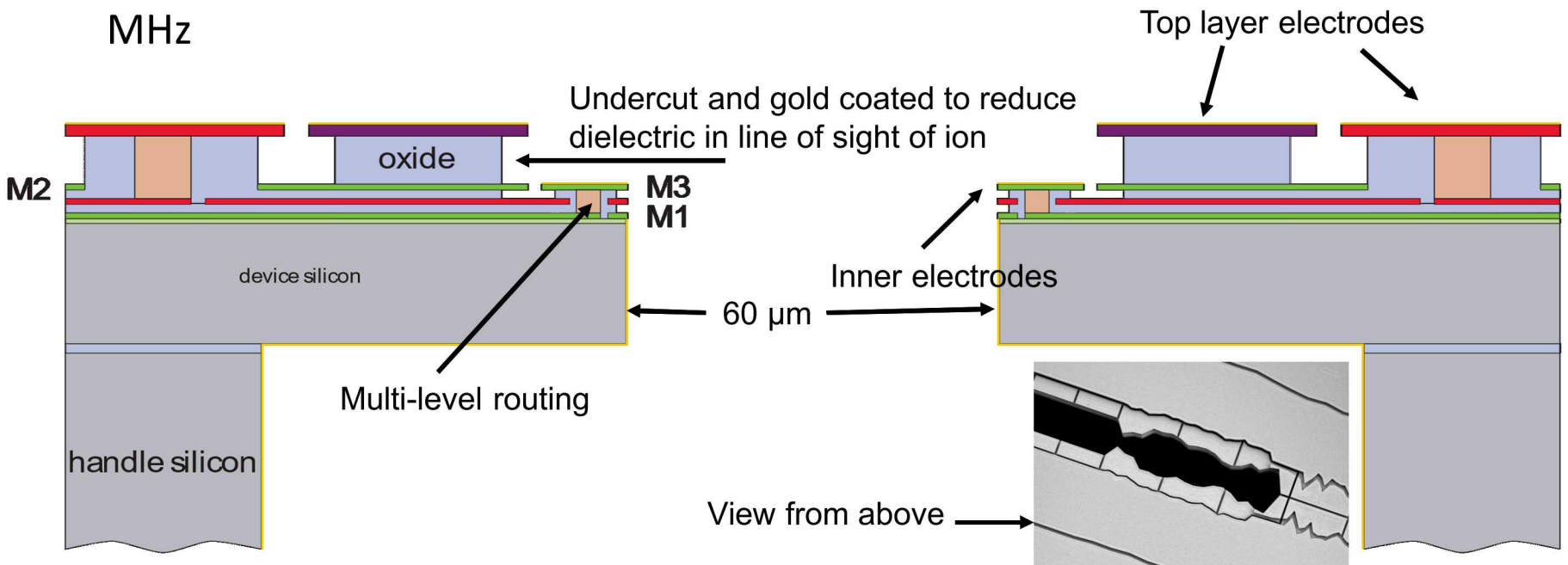
- Standardization (lithographically defined electrodes)
- Multi-unit production
- Multi-level lead routing for accessing interior electrodes
 - Connecting both control and RF electrodes
 - Any 2D topology is possible
- Voltage breakdown $>300\text{ V}$ @ $\sim 50\text{ MHz}$
- Overhung electrodes
- Low electric field noise (heating)
- Backside loading holes
- Trench capacitors
- High optical access (delivery and collection)



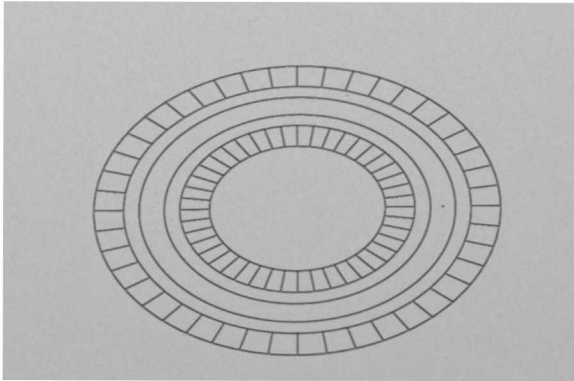
Capabilities & Requirements

Derived requirements

- Standardization (lithographically defined electrodes)
- Multi-unit production
- **Multi-level lead routing for accessing interior electrodes**
- Voltage breakdown $>300\text{ V}$ @ $\sim 50\text{ MHz}$
- **Overhung electrodes**
- Low electric field noise (heating)
- Backside loading holes
- Trench capacitors
- High optical access (delivery and collection)

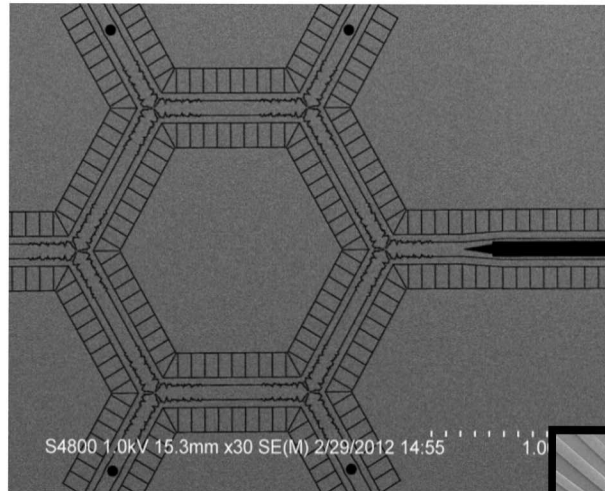


Unique Traps From Sandia



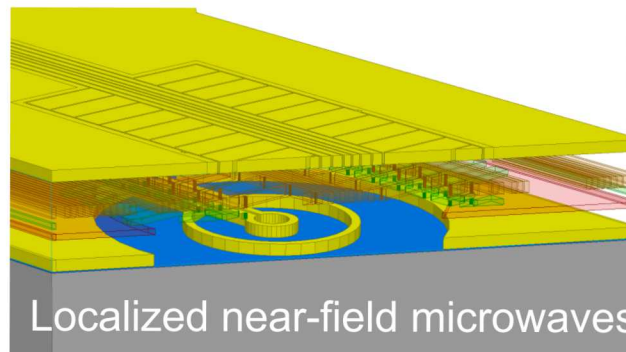
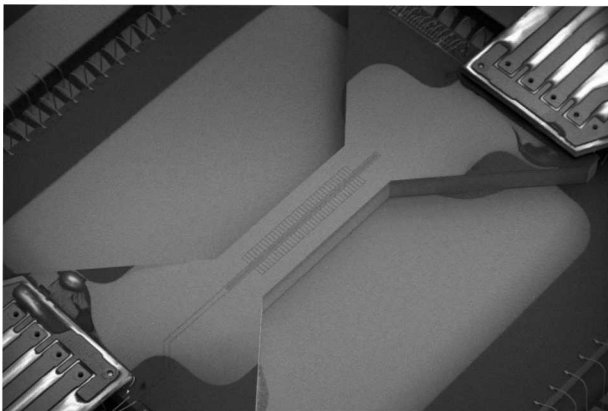
Ring trap

Tabakov, B et al. *Phys. Rev. Applied* **4**, 031001 (2015).

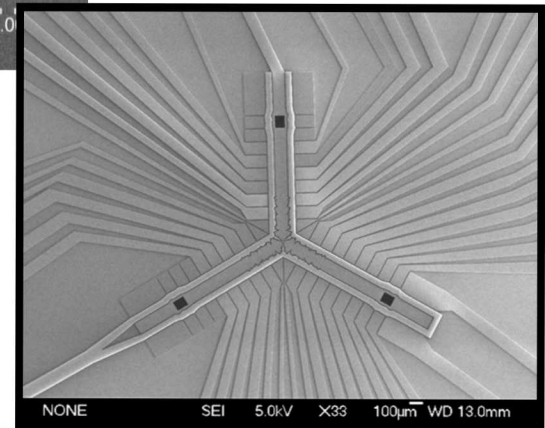


Circulator Trap

Microwave trap



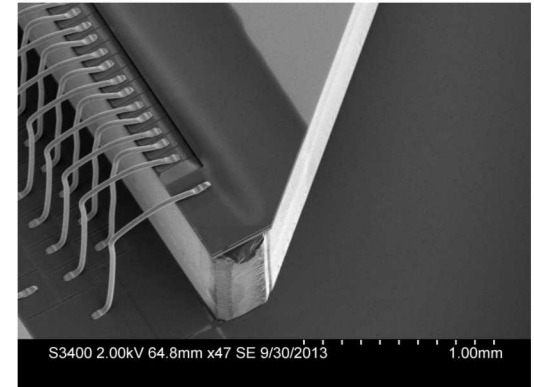
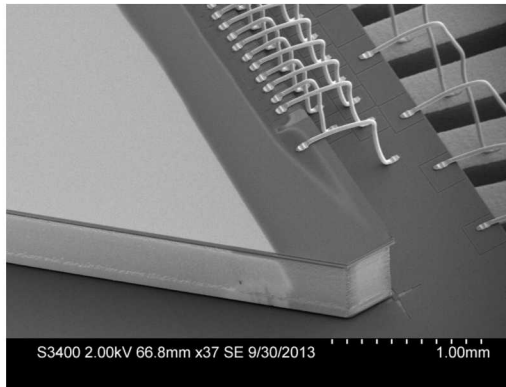
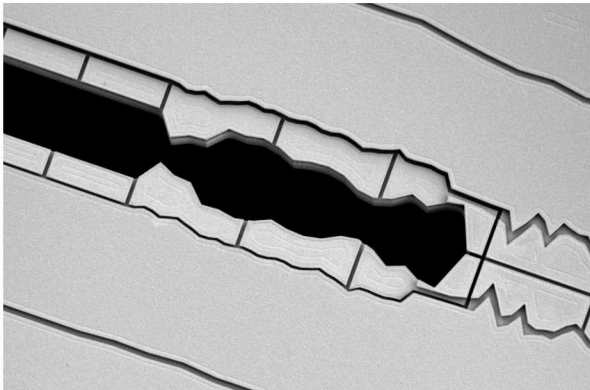
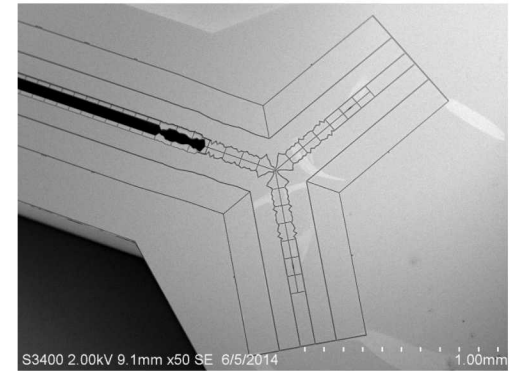
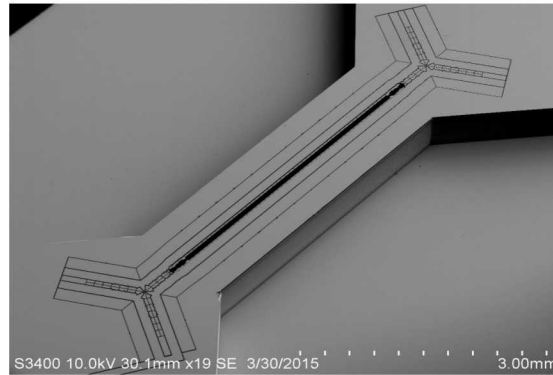
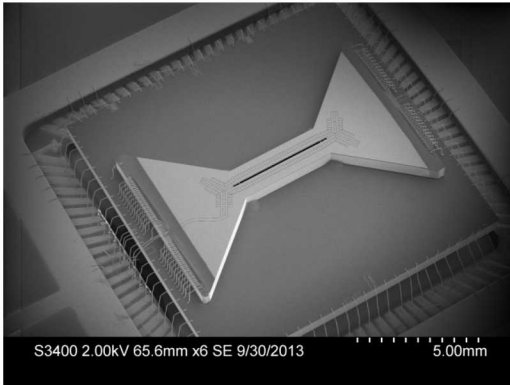
Localized near-field microwaves



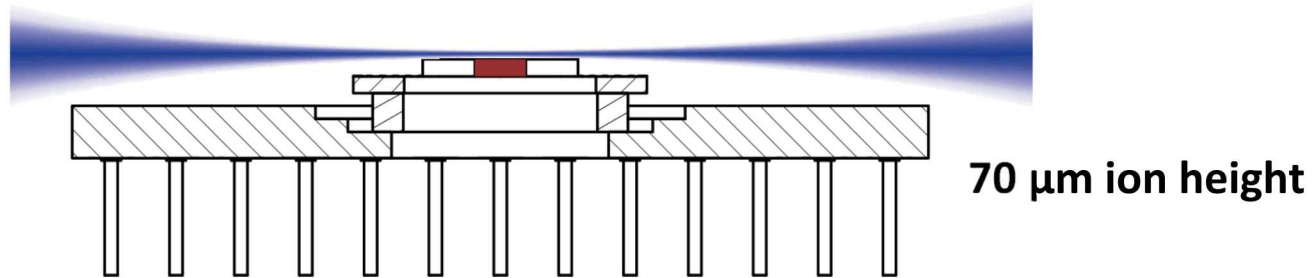
Y-junction trap

330 ns π -time, 10^{-5} single qubit gate errors

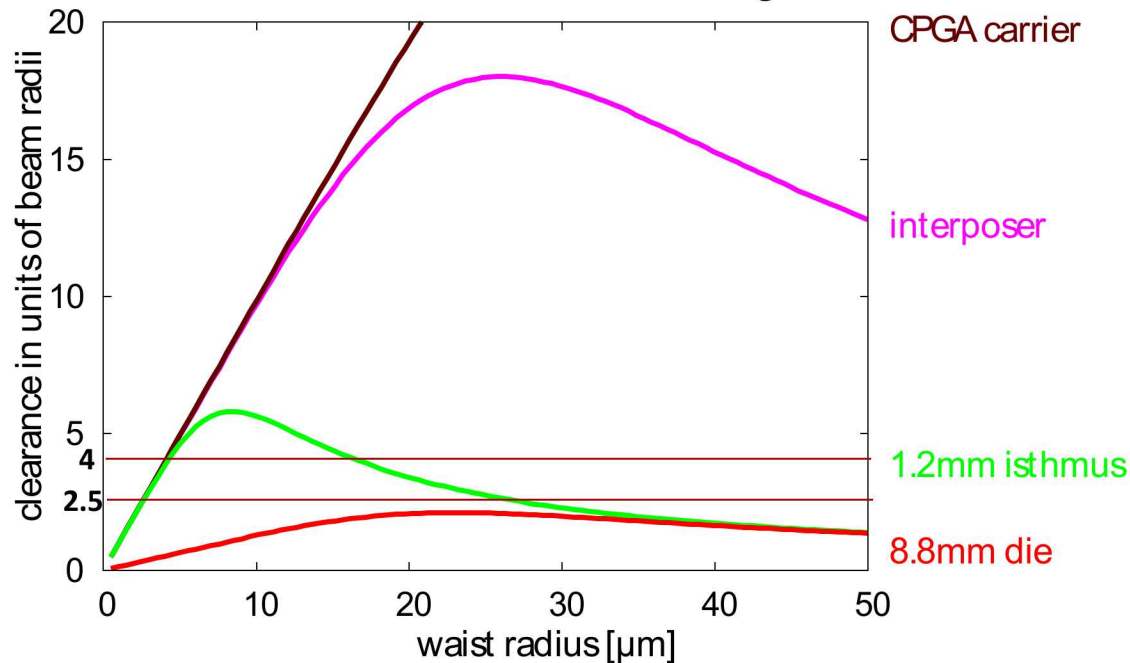
High Optical Access (HOA)



High Optical Access (HOA)



clearance for a surface skimming beam



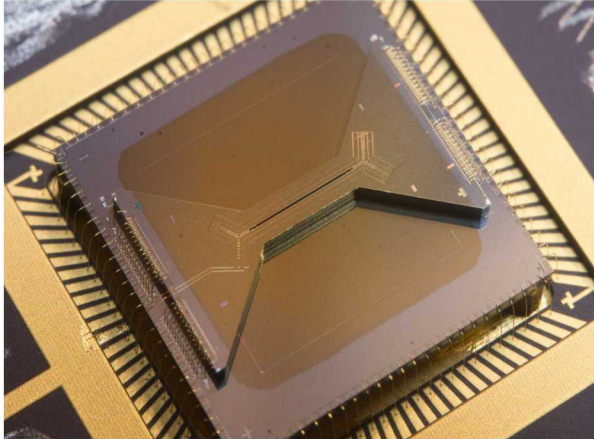
4: $<2 \times 10^{-14}$

3: $<2 \times 10^{-8}$

2.5: $<3 \times 10^{-6}$

4 μm waist is possible

High Optical Access (HOA)

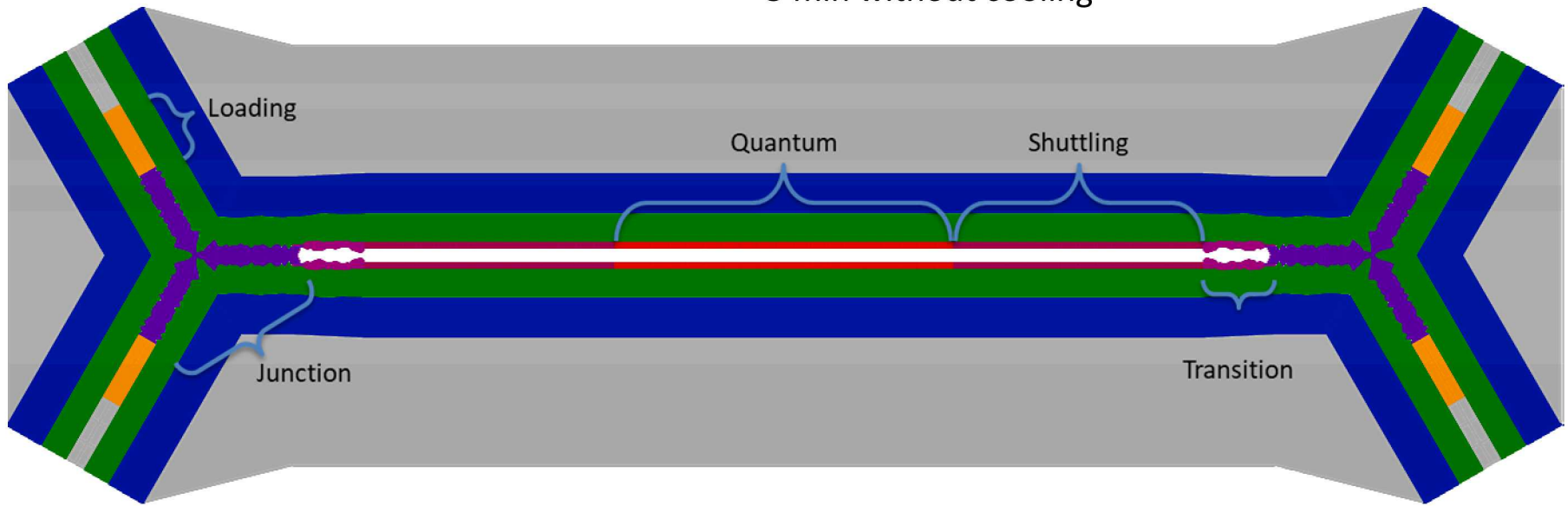


Optical access

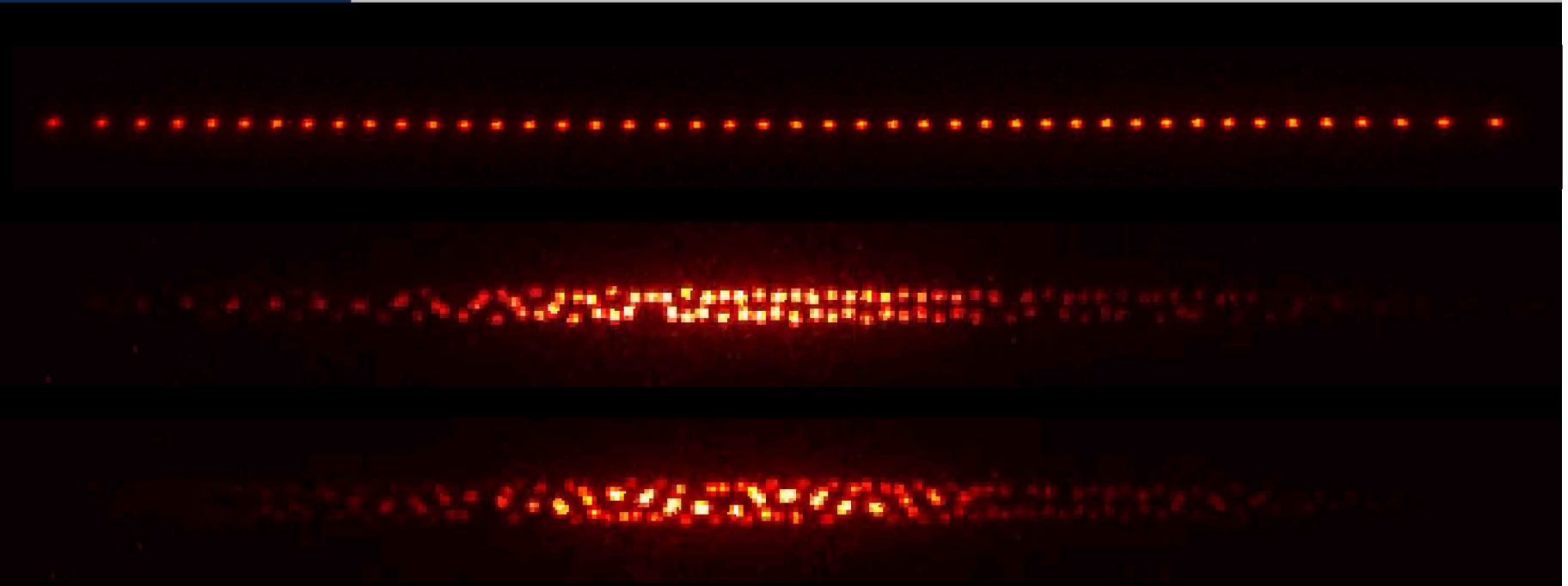
- Excellent optical access rivaling 3-D

Trap strength (Typical Yb^+)

- Radial trap frequency 2 - 5 MHz
- RF frequency 50 MHz
- Stable for long ion chains
- Low heating rates (30 q/s parallel to surface, 125 q/s perpendicular)
- >100 h observed (while running measurements)
- >5 min without cooling



Trapped ion chains



- Observed storage times between
 - 16 min for long linear chain
 - 16 h for 3d crystal
- Most likely limited by background collisions
- Property of vacuum conditions
- Losing all ions at once (one might come back)

Electric Field Control

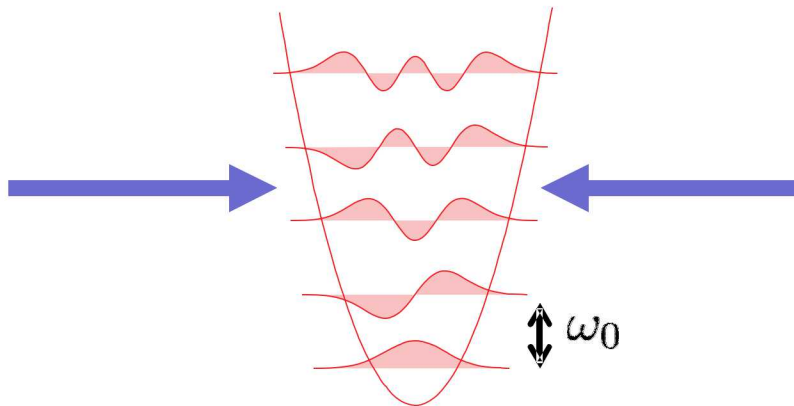
When ions are trapped, they exhibit vibrational modes the trapping directions.

Secular Frequency: One for each trapping direction

The motional modes are important:

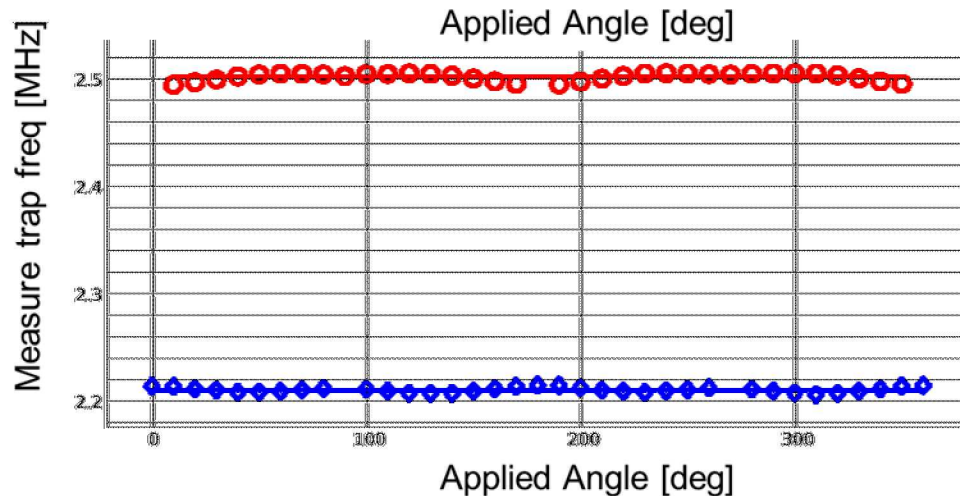
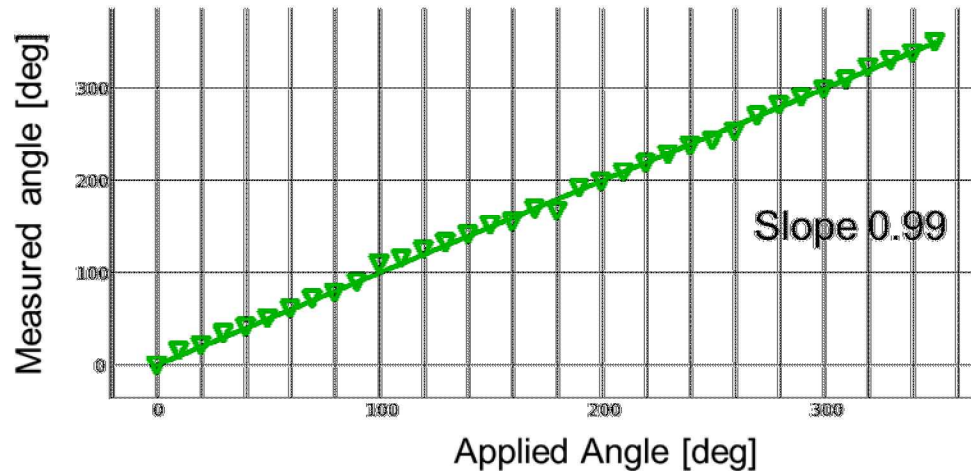
- Interactions between ions
- Allow for cooling to the ground state
- Dictate sensitivity to noise sources

The frequency of the modes are controlled by the strength of the trap



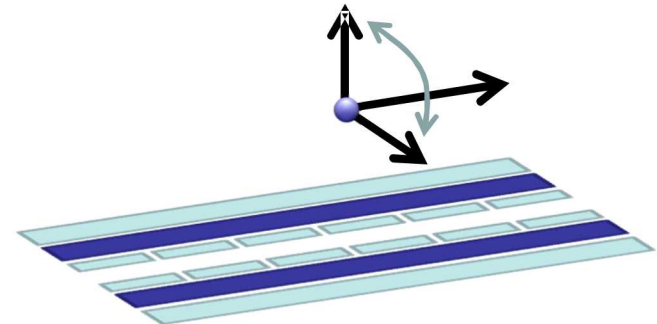
Stronger fields have the effect of a narrowing the well, and thus larger secular frequencies

Electric Field Modeling from Trap Design is Accurate

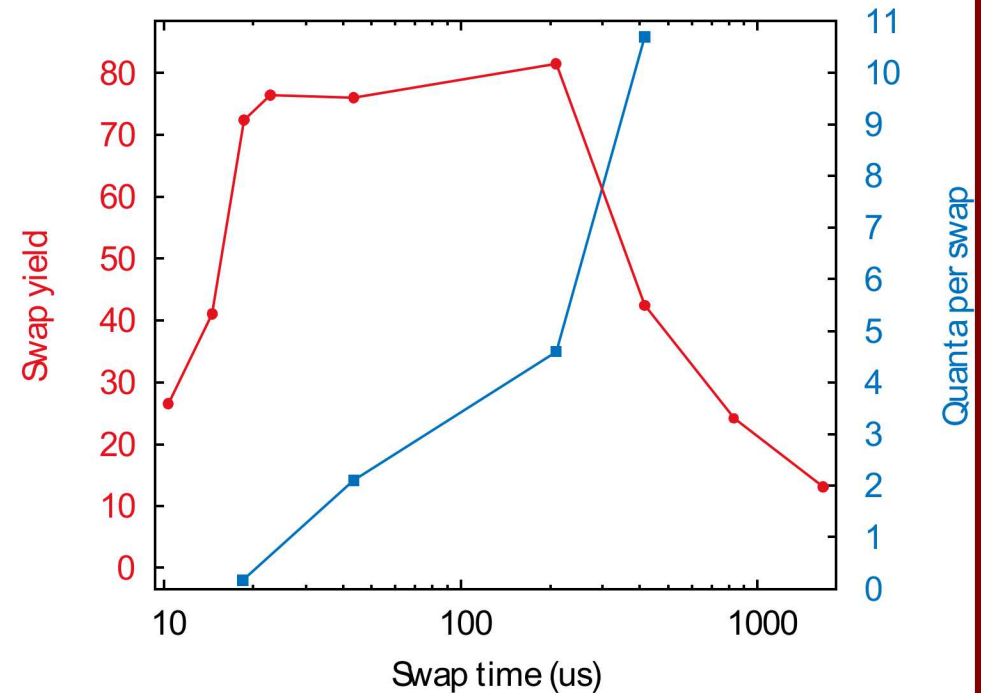
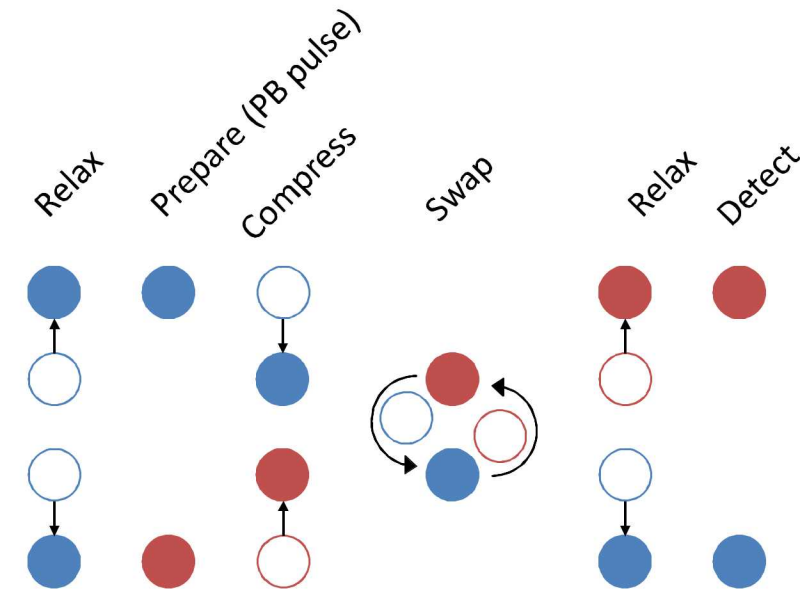


Electric field control

- Do we understand the trapping fields?
- Principal axes rotation realized as in simulation
- No change in trap frequencies
- The simulations accurately describe the fields and curvatures generated by the trap



Electric Field Control from Surface Traps: Swapping ions



Advantages of parametric trapping solutions:

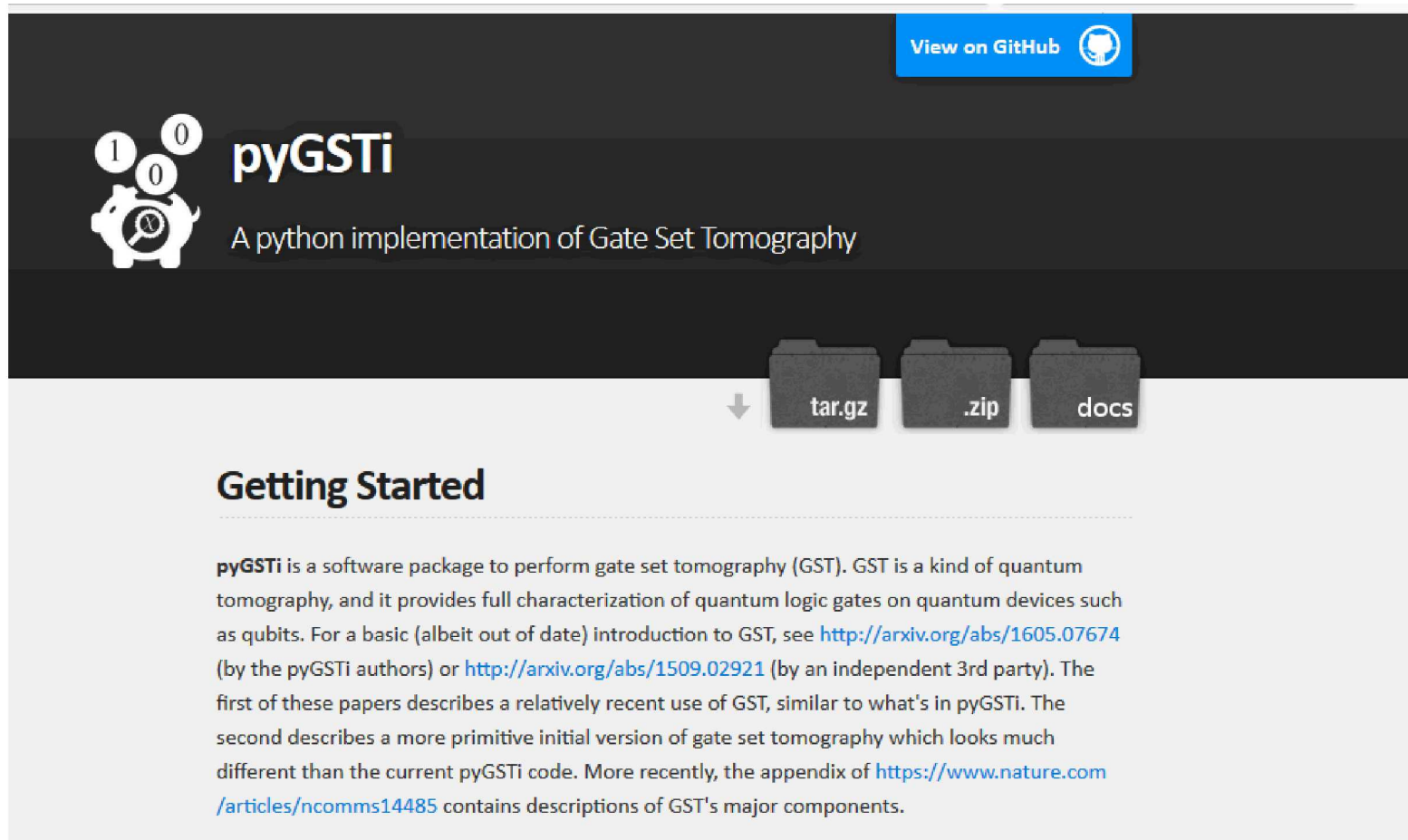
- Primitives in terms of curvature tensor elements and can be applied at any location in the trap.
- Shuttling primitives can be easily combined
- Example: rotating ion crystal while translating through the trap

Testing High Fidelity Operations with GST

Gate Set Tomography, developed at Sandia
Robin Blume-Kohout, Erik Nielsen, et al.

<http://www.pygsti.info/>

Available on GitHub: <https://github.com/pyGSTio/pyGSTi>



The screenshot shows the GitHub repository page for pyGSTi. At the top right is a blue button labeled "View on GitHub" with the GitHub logo. On the left is the repository logo, which features a piggy bank with a magnifying glass and three coins labeled "1", "0", and "0". To the right of the logo is the text "pyGSTi" and "A python implementation of Gate Set Tomography". Below this, there are three folder icons labeled "tar.gz", ".zip", and "docs". A downward arrow is positioned to the left of the "tar.gz" folder. The main heading "Getting Started" is followed by a paragraph of text.

pyGSTi
A python implementation of Gate Set Tomography

tar.gz .zip docs

Getting Started

pyGSTi is a software package to perform gate set tomography (GST). GST is a kind of quantum tomography, and it provides full characterization of quantum logic gates on quantum devices such as qubits. For a basic (albeit out of date) introduction to GST, see <http://arxiv.org/abs/1605.07674> (by the pyGSTi authors) or <http://arxiv.org/abs/1509.02921> (by an independent 3rd party). The first of these papers describes a relatively recent use of GST, similar to what's in pyGSTi. The second describes a more primitive initial version of gate set tomography which looks much different than the current pyGSTi code. More recently, the appendix of <https://www.nature.com/articles/ncomms14485> contains descriptions of GST's major components.

How Gate Set Tomography (GST) Works

Start with a few gates that you want to test:

X: $\pi/2$ rotation about x-axis

Y: $\pi/2$ rotation about y-axis

i: idle gate (do nothing)

GST uses those gates to form “**germs**” which are small sets of these primitive gates

X, Y, i, XY, XYi, XiY, Xii, Yii, XXiY, XYYi, XXYXYY

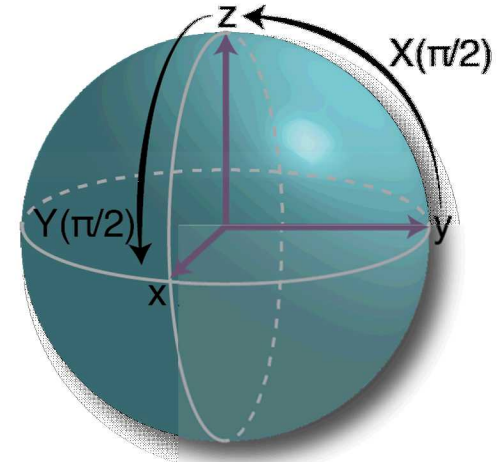
GST uses a small set of “**fiducials**” made of the primitives for preparation and measurement (six orthogonal poles)

{}, X, Y, XX, XXX, YYY

Using combinations of

fiducial1 – (germ)ⁿ – fiducial2

To make strings of gates that are applied to the system



GST is:

- Self Consistent** (fiducials are not assumed perfect)
- Efficient** (repeating germs amplifies the errors)
- Sensitive** (germs chosen to be sensitive to all types of errors)

Information that GST Reports

Many different ways to report fidelity
Ask your theorist which is preferred!
GST gives you all of these:

Entanglement Infidelity

Average Gate Infidelity

Non-Unitary Entanglement Infidelity

Non-Unitary Average Gate Infidelity

$\frac{1}{2}$ Diamond-Distance

$\frac{1}{2}$ Non-Unitary Diamond-Distance

Randomized Benchmarking Number

Eigenvalues and Matrices

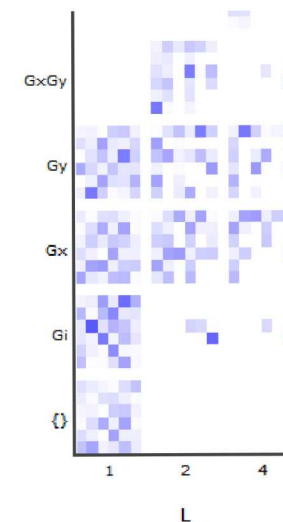
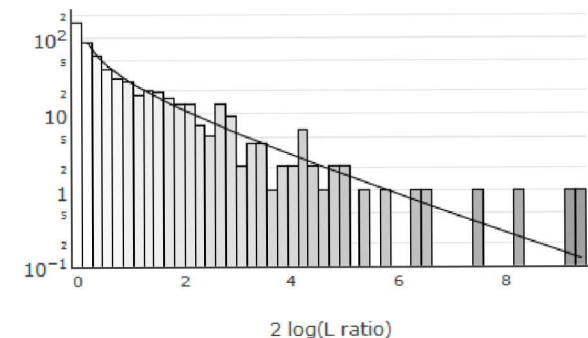
Gate Decompositions

Gate Error Generators

Estimated Rotation Angles

Rotation Angles between Gates

Along with visuals to more quickly detect patterns of errors



Summary

Model Violation

Overview

Per-sequence detail

Robust data scaling

Gauge Invariant Error Metrics

Overview

Germes Detail

Gauge Dependent Error Metrics

Overview

Raw Estimates

Gate Decompositions

Gate Error Generators

For Reference

Input Reference

System Reference

Help

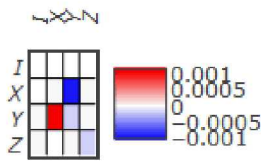
Estimate

CPTP,Robust+

C-Opt Param	Value
0: Item weights	gates=1, spam=0
0: Gauge group	Unitary
1: SPAM penalty factor	1.0
1: Item weights	gates=0, spam=1
1: Gauge group	TP Spam

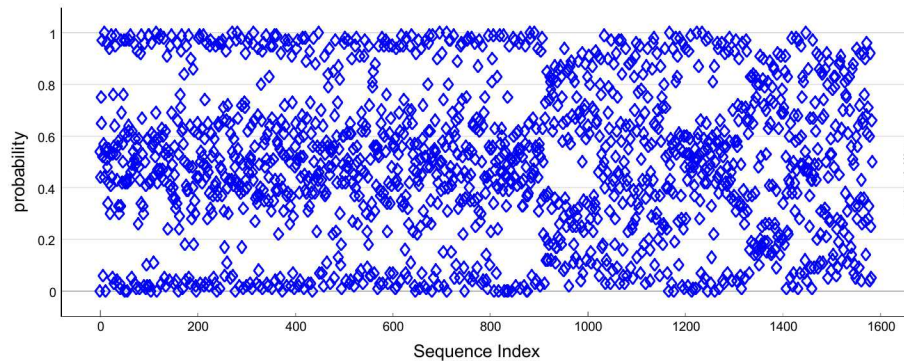
Information that GST Reports

Different Types of Error Generators

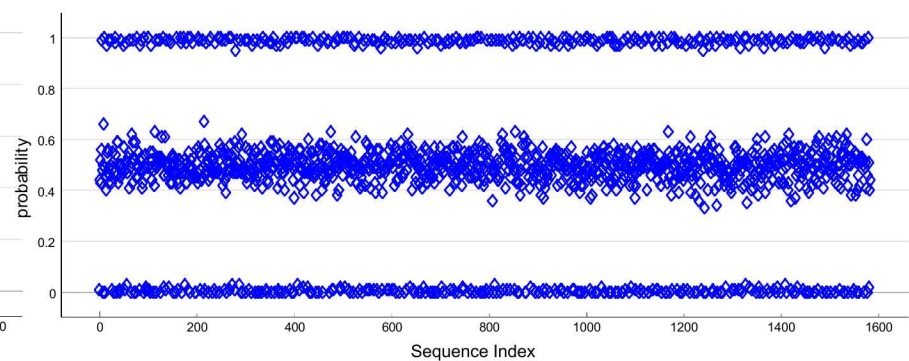
Gate	Error Generator	Pauli Hamiltonian Projections	Pauli Stochastic Projections	Pauli Affine Projections																								
Gi		Power 0.96 <div>Q1</div> <table><tr><td>I</td><td>X</td><td>Y</td><td>Z</td></tr><tr><td>0</td><td>1m5</td><td>5m6</td><td>5m4</td></tr></table>	I	X	Y	Z	0	1m5	5m6	5m4	Power 0.032 <div>Q1</div> <table><tr><td>I</td><td>X</td><td>Y</td><td>Z</td></tr><tr><td>-1m4</td><td>9m5</td><td>9m6</td><td>1m6</td></tr></table>	I	X	Y	Z	-1m4	9m5	9m6	1m6	Power 0.00075 <div>Q1</div> <table><tr><td>I</td><td>X</td><td>Y</td><td>Z</td></tr><tr><td>0</td><td>1m5</td><td>-2m5</td><td>-3m5</td></tr></table>	I	X	Y	Z	0	1m5	-2m5	-3m5
I	X	Y	Z																									
0	1m5	5m6	5m4																									
I	X	Y	Z																									
-1m4	9m5	9m6	1m6																									
I	X	Y	Z																									
0	1m5	-2m5	-3m5																									
Gx		Power 1 <div>Q1</div> <table><tr><td>I</td><td>X</td><td>Y</td><td>Z</td></tr><tr><td>0</td><td>-3m4</td><td>4m6</td><td>4m6</td></tr></table>	I	X	Y	Z	0	-3m4	4m6	4m6	Power 0.00011 <div>Q1</div> <table><tr><td>I</td><td>X</td><td>Y</td><td>Z</td></tr><tr><td>-4m6</td><td>4m7</td><td>2m6</td><td>2m6</td></tr></table>	I	X	Y	Z	-4m6	4m7	2m6	2m6	Power 6.1e-05 <div>Q1</div> <table><tr><td>I</td><td>X</td><td>Y</td><td>Z</td></tr><tr><td>0</td><td>6m6</td><td>-2m6</td><td>-2m6</td></tr></table>	I	X	Y	Z	0	6m6	-2m6	-2m6
I	X	Y	Z																									
0	-3m4	4m6	4m6																									
I	X	Y	Z																									
-4m6	4m7	2m6	2m6																									
I	X	Y	Z																									
0	6m6	-2m6	-2m6																									
Gy		Power 0.041 <div>Q1</div> <table><tr><td>I</td><td>X</td><td>Y</td><td>Z</td></tr><tr><td>0</td><td>4m6</td><td>2m5</td><td>-4m6</td></tr></table>	I	X	Y	Z	0	4m6	2m5	-4m6	Power 0.59 <div>Q1</div> <table><tr><td>I</td><td>X</td><td>Y</td><td>Z</td></tr><tr><td>-1m4</td><td>3m5</td><td>3m5</td><td>3m5</td></tr></table>	I	X	Y	Z	-1m4	3m5	3m5	3m5	Power 0.15 <div>Q1</div> <table><tr><td>I</td><td>X</td><td>Y</td><td>Z</td></tr><tr><td>0</td><td>4m5</td><td>-9m5</td><td>-6m5</td></tr></table>	I	X	Y	Z	0	4m5	-9m5	-6m5
I	X	Y	Z																									
0	4m6	2m5	-4m6																									
I	X	Y	Z																									
-1m4	3m5	3m5	3m5																									
I	X	Y	Z																									
0	4m5	-9m5	-6m5																									

GST – Microwaves (horn)

Raw data poor gates

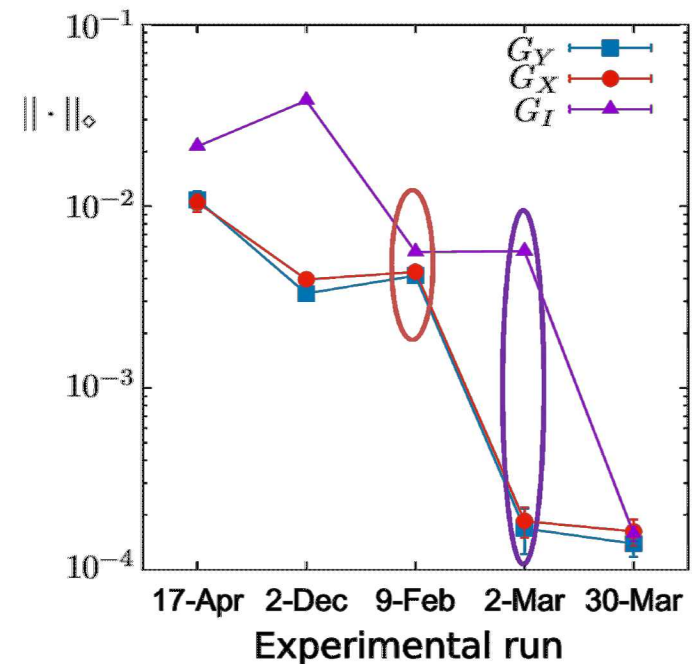


Raw data good gates



Gate	Rotn. axis	Angle
G_I	0.5252	0.001699π
	-0.009	
	0.8506	
	-0.0244	
G_X	-3×10^{-6}	0.501308π
	-1	
	-3×10^{-5}	
	-0.009	
G_Y	-0.2474	0.501366π
	0.0001	
	0.9689	
	-0.0001	

Gate	Rotn. axis	Angle
G_I	-0.0035	0.001769π
	0.014	
	-0.9999	
	0.0006	
G_X	-3×10^{-5}	0.500007π
	-1	
	1×10^{-4}	
	0.0006	
G_Y	0.1104	0.50001π
	4×10^{-5}	
	0.9939	
	0.0005	



Microwave Gates using Microwave Trap (Single Qubit)

GST Results

Gate	Gi	Gx	Gy
Ent. Infidelity	1.4×10^{-5}	3.5×10^{-5}	2.1×10^{-5}
Avg. Gate Infidelity	9.2×10^{-6}	2.3×10^{-5}	1.4×10^{-5}
Non-U. Ent. Infidelity	1.4×10^{-5}	3.5×10^{-5}	2.1×10^{-5}
Non U. Avg. Gate Infidelity	9.2×10^{-6}	2.3×10^{-5}	1.4×10^{-5}
½ Diamond-Dist.	6.5×10^{-4}	2.4×10^{-4}	1.3×10^{-4}
½ Non-U. Diamond-Dist	1.4×10^{-5}	3.9×10^{-5}	2.3×10^{-5}

Entanglement Infidelity $< 3.5 \times 10^{-5}$
½ diamond norm $< 6.5 \times 10^{-4}$ } Indicates Systematic Error

Laser based Raman gates



co-propagating beam geometry

- Motion independent
- No optical phase imprinted

- BB1 dynamically compensated pulse sequences

GST results:

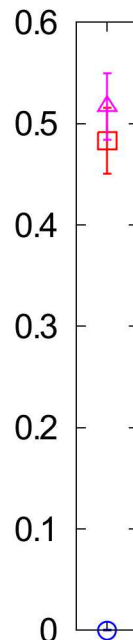
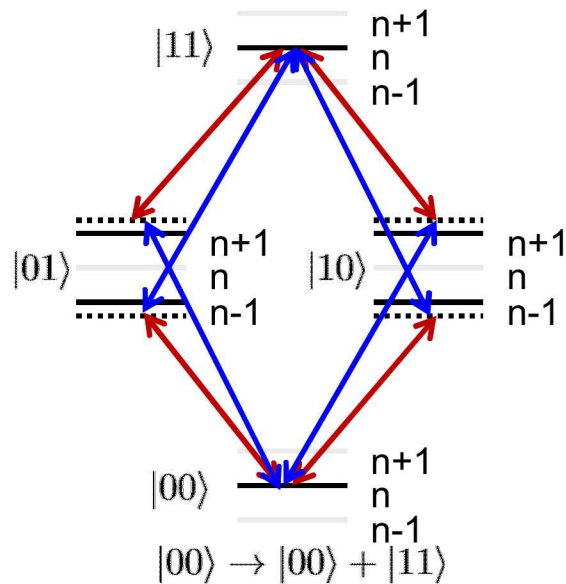
95% confidence intervals

Gate	Conventional pulses		Gapless pulses	
	Process Infidelity	1/2 \diamond -Norm	Process Infidelity	1/2 \diamond -Norm
G_I	$0.05(2) \times 10^{-4}$	$12(1) \times 10^{-4}$	$1.1(1) \times 10^{-4}$	$5.3(2) \times 10^{-4}$
G_X	$1.3(1) \times 10^{-4}$	$4(2) \times 10^{-4}$	$0.5(1) \times 10^{-4}$	$2(6) \times 10^{-4}$
G_Y	$1.6(4) \times 10^{-4}$	$4(3) \times 10^{-4}$	$0.7(1) \times 10^{-4}$	$4(9) \times 10^{-4}$

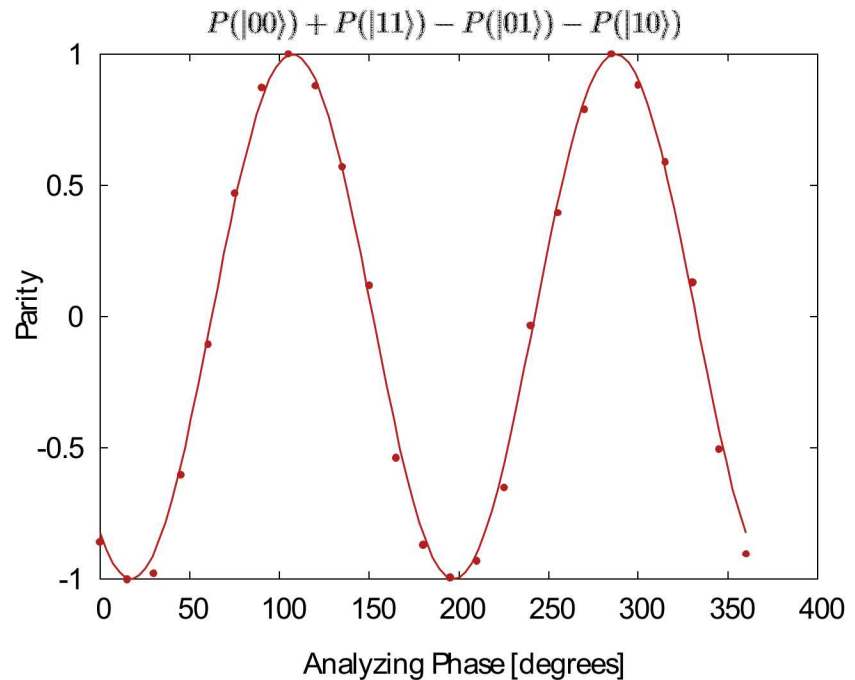
Process Infidelity: 1.2×10^{-4}
1/2 \diamond -Norm: 5.3×10^{-4}

Mølmer-Sørensen gates

- Mølmer-Sørensen gates [1]
- All two-qubit gates implemented using Walsh compensation pulses [2]



Zero bright □
One bright ○
Two bright △

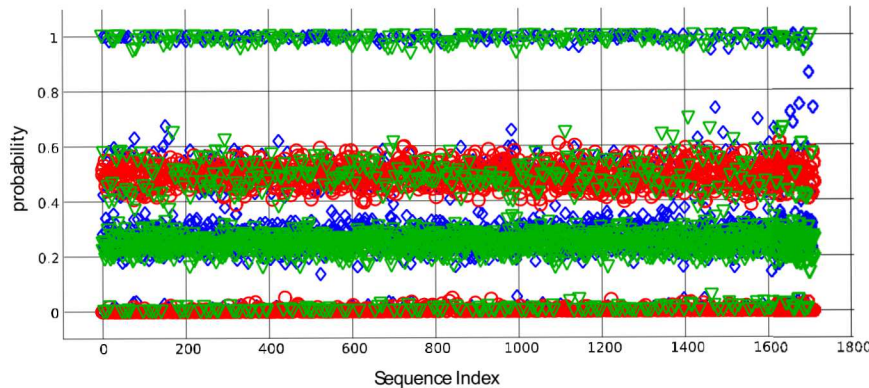


$$\mathcal{F} = \frac{1}{2}(P(|00\rangle) + P(|11\rangle)) + \frac{1}{4}c \approx 0.995$$

[1] K. Mølmer, A. Sørensen, PRL 82, 1835 (1999)

[2] D. Hayes et al. Phys. Rev. Lett. 109, 020503 (2012)

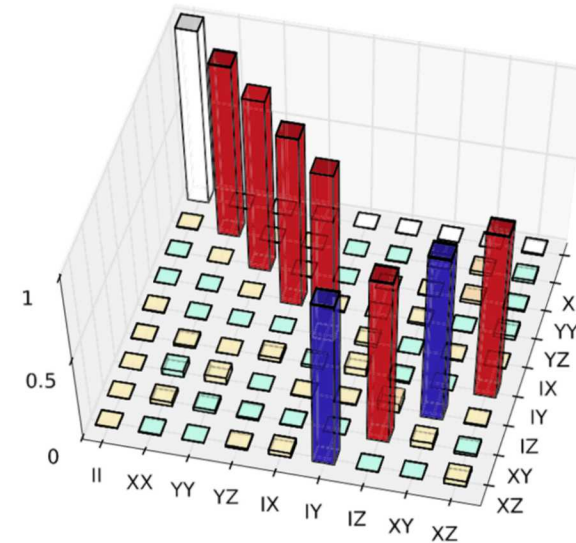
GST on symmetric subspace



Zero ions bright

One ion bright

Two ions bright



Gate	Process infidelity	$\frac{1}{2}$ Diamond norm
G_I	$1.6 \times 10^{-3} \pm 1.6 \times 10^{-3}$	$28 \times 10^{-3} \pm 7 \times 10^{-3}$
G_{XX}	$0.4 \times 10^{-3} \pm 1.0 \times 10^{-3}$	$27 \times 10^{-3} \pm 5 \times 10^{-3}$
G_{YY}	$0.1 \times 10^{-3} \pm 0.9 \times 10^{-3}$	$26 \times 10^{-3} \pm 4 \times 10^{-3}$
G_{MS}	$4.2 \times 10^{-3} \pm 0.6 \times 10^{-3}$	$38 \times 10^{-3} \pm 5 \times 10^{-3}$

95% confidence intervals

Process fidelity of two-qubit Mølmer-Sørensen gate > 99.5%

Summary

Surface Traps fabricated at Sandia demonstrate a many building blocks for larger systems: Good Platform for Future

- Ion shuttling and position control
- High fidelity quantum operations

Leveraging DOE facilities

- MESA facility – capabilities align well with trap requirements
 - Engineers and technologists essential to fabricating and packaging the many traps needed at SNL and academic/commercial partners
- Engineering and simulations
 - Microwave design
 - Quantum theory – tomography and error correction

Future research

- Next Slide!



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Future Work with Ions at Sandia

Department of Energy

Department of Energy Announces \$218 Million for Quantum Information Science

SEPTEMBER 24, 2018

[Home](#) » Department of Energy Announces \$218 Million for Quantum Information Science

Field Will Shape Future of Information Processing

WASHINGTON, D.C. – Today, the **U.S. Department of Energy (DOE)** announced \$218 million in funding for 85 research awards in the important emerging field of Quantum Information Science (QIS). The awards were made in conjunction with the White House Summit on Advancing American Leadership in QIS, highlighting the high priority that the Administration places on advancing this multidisciplinary area of research, which is expected to lay the foundation for the next generation of computing and information processing as well as an array of other innovative technologies.

Future Work with Ions at Sandia

QSCOUT: DOE funded, goal of making a stable, public platform (testbed) from trapped ions for the scientific community to perform experiments

LogiQ: IARPA funded, goal of making a logical qubit with errors rates less than the physical qubits that compose it

www.sandia.gov → Careers → View All Jobs

Postdoctoral Appointee – AMO Physics Job ID 663692

Ion Trapping

Peter Maunz (plmaunz@sandia.gov)

Postdoctoral Appointee – AMO Physics Job ID 663398

Atomic Sensing and Clocks

Peter Schwint (pschwin@sandia.gov)

Two-qubit gates in Rydberg atoms, atom interferometers

Grant Biedermann (gbeider@sandia.gov)

Summary

Surface Traps fabricated at Sandia demonstrate many building blocks for larger systems:

- Ion shuttling and position control
- High fidelity quantum operations
- Beginning sympathetic cooling

Leveraging DOE facilities

- MESA facility – capabilities align well with trap requirements
 - Engineers and technologists essential to fabricating and packaging the many traps needed at SNL and academic/commercial partners
- Engineering and simulations
 - Microwave design
 - Quantum theory – tomography and error correction

Future research

- DOE testbed
- LogiQ research

Trap design and fabrication

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Trap design and experimental work

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Melissa Revelle
Dan Stick
Christopher Yale

RF Engineering

Christopher Nordquist
Stefan Lepkowski

Trap packaging

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GST protocols

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